

ON Semiconductor®

FDD2670

200V N-Channel PowerTrench® MOSFET

General Description

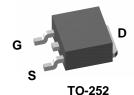
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers.

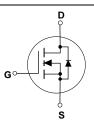
These MOSFET's feature faster switching and lower gate charge than other MOSFET's with comparable $RDS_{(\text{ON})}$ specifications.

The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.

Features

- 3.6 A, 200 V. $R_{DS(ON)} = 130 \text{ m}\Omega$ @ $V_{GS} = 10 \text{ V}$
- Low gate charge
- Fas t switching speed
- High performance trench technology for extremely low $R_{\mbox{\scriptsize DS(ON)}}$
- · High power and current handling capability





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		200	V
V _{GSS}	Gate-Source Voltage		±20	V
I _D	Drain Current - Continuous	(Note 1)	3.6	Α
	Drain Current - Pulsed		20	
P _D	Maximum Power Dissipation @ T _C = 25°C	(Note 1)	70	W
	@ T _A = 25°C	(Note 1a)	3.2	
	@ T _A = 25°C	(Note 1b)	1.3	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	3.2	V/ns
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	1.8	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1b)	96	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDD2670	FDD2670	13"	16mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-So	ource Avalanche Ratings (Note	1)		I		
W _{DSS}	Single Pulse Drain-Source Avalanche Energy	$V_{DD} = 100 \text{ V}, I_D = 3.6 \text{ A}$			375	mJ
I _{AR}	Maximum Drain-Source Avalanche Current				3.6	Α
Off Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	200			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		214		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 160 V, V _{GS} = 0 V			1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	NA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	NA
On Char	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2	4	4.5	V
$\Delta V_{GS(th)} \ \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		-10		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	V _{GS} = 10 V, I _D = 3.6 A V _{GS} = 10 V, I _D = 3.6 A T _J = 125°C		100 205	130 275	mΩ
I _{D(on)}	On–State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 5 \text{ V}$	20			Α
g FS	Forward Transconductance	$V_{DS} = 5 \text{ V}, \qquad I_{D} = 3.6 \text{ A}$		15		S
Dynamic	: Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = 100 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		1228		PF
Coss	Output Capacitance	f = 1.0 MHz		112		PF
C _{rss}	Reverse Transfer Capacitance			17		pF
Switchin	g Characteristics (Note 2)					
$t_{\text{d(on)}}$	Turn-On Delay Time	$V_{DD} = 100 \text{ V}, \qquad I_D = 1 \text{ A},$		13	23	ns
t _r	Turn–On Rise Time	V_{GS} = 10 V, R_{GEN} = 6 Ω		8	16	ns
$t_{d(off)}$	Turn-Off Delay Time			30	48	ns
t _f	Turn-Off Fall Time			25	40	ns
Q_g	Total Gate Charge	$V_{DS} = 100 \text{ V}, \qquad I_{D} = 3.6 \text{ A},$		27	43	nC
Q_{gs}	Gate–Source Charge	V _{GS} = 10 V		7		nC
Q_{gd}	Gate-Drain Charge			10		nC
Drain-So	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain-Source	Diode Forward Current			2.1	Α
V_{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 2.1 \text{ A} \text{(Note 2)}$		0.7	1.2	V

^{1.} $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.

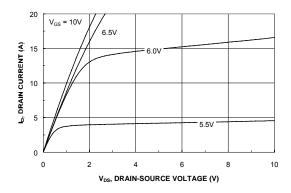


Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width < 300 μ s, Duty Cycle < 2.0%

3. $I_{SD} \leq 3A, \ di/dt \leq 100A/\mu s, \ V_{DD} \leq BV_{DSS}, \ Starting \ T_J$ = $25^{\circ}C$

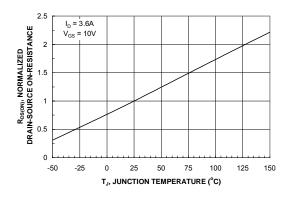
Typical Characteristics



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Figure 1. On-Region Characteristics.

Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.



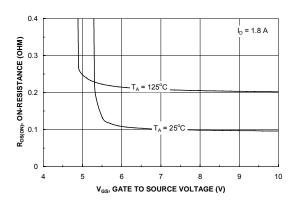
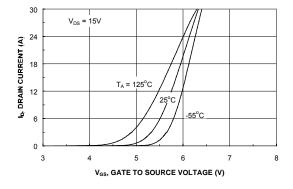


Figure 3. On-Resistance Variation with Temperature.

Figure 4. On-Resistance Variation with Gate-to-Source Voltage.



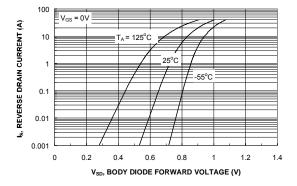
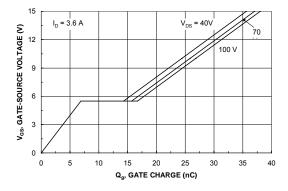


Figure 5. Transfer Characteristics.

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



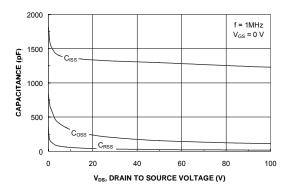


Figure 7. Gate Charge Characteristics.

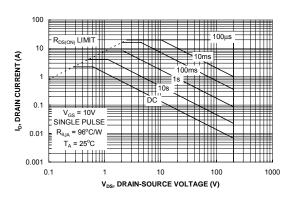


Figure 8. Capacitance Characteristics.

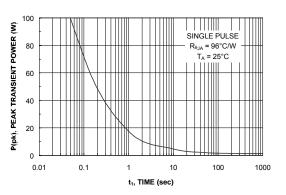


Figure 9. Maximum Safe Operating Area.



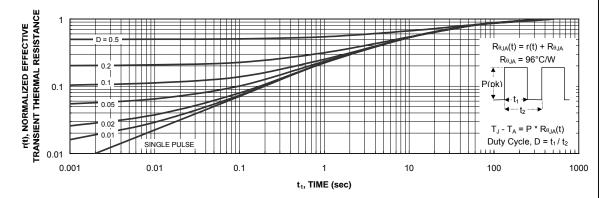


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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